CLAIMS

- 1. A sub-atmospheric downstream pressure control apparatus (200), characterized by:
- 5 a first flow restricting element (FRE)(202);
 - a pressure control chamber (PCC) (204) located in serial fluidic communication downstream from said first FRE;
 - a second FRE (206) located in serial fluidic communication downstream from said PCC;
- 10 a gas source (208); and
 - a flow controlling device (210) in serial fluidic communication downstream from said gas source and upstream from said PCC.
 - 2. A sub-atmospheric downstream pressure control apparatus as in claim 1 further characterized by:
- a reactive gas source (422) connected in serial fluidic communication upstream from said PCC; and
 - an abatement element (420) located within said PCC.
 - 3. A sub-atmospheric downstream pressure control apparatus as in claim 1 further characterized by:
- a third FRE (504) connected in serial fluidic communication downstream from said PCC;
 - an abatement chamber (502) connected in serial fluidic communication downstream from said third FRE;
- a reactive gas source (506) connected in serial fluidic communication upstream from said abatement chamber; and
 - an abatement element (520) disposed within said abatement chamber.
 - 4. A sub-atmospheric downstream pressure control apparatus as in claim 1 wherein a process chamber (304) is located in serial fluidic communication upstream from said first FRE;
- 30 said process chamber and said PCC (308) are formed as compartments within a single process vessel (324); and
 - said first FRE (306) is formed within the partition between said process chamber and said PCC.

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5. A wafer processing apparatus comprising a process chamber (10), said apparatus characterized by:

- a process reactive gas supply line (12) from a process gas source in serial fluidic communication upstream from said process chamber;
- 5 an upstream flow control device located in serial fluidic communication upstream from said process chamber and downstream from said process gas source;
 - a first flow restricting element (202) located in serial fluidic communication downstream from said process chamber;
 - a pressure control chamber (PCC) (204) located in serial fluidic communication downstream from said first FRE;
 - a second FRE (206) located in serial fluidic communication downstream from said PCC;
 - a gas source (208); and

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- a flow controlling device (210) in serial fluidic communication downstream from said gas source and upstream from said PCC.
- 6. A sub-atmospheric downstream pressure control apparatus as in claim 5 further characterized by:
- a reactive gas source (422) connected in serial fluidic communication upstream from said PCC; and
- 20 an abatement element (420) located within said PCC.
 - 7. A sub-atmospheric downstream pressure control apparatus as in claim 5 further characterized by:
 - a third FRE (504) connected in serial fluidic communication downstream from said PCC (200);
- an abatement chamber (500) connected in serial fluidic communication upstream from said third FRE;
 - a reactive gas source (506) connected in serial fluidic communication upstream from said abatement chamber; and
 - an abatement element (520) located within said abatement chamber.
- 8. A sub-atmospheric downstream pressure control apparatus as in claim 5 wherein a process chamber (304) is located in serial fluidic communication upstream from said first FRE (306);
 - said process chamber and said PCC (308) are formed as compartments within a single process vessel (324); and

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said first FRE is formed within the partition between said process chamber and said PCC.

- , 9. A sub-atmospheric downstream pressure control apparatus as in claim 5 wherein said process is LPCVD.
- 10. A sub-atmospheric downstream pressure control apparatus as in claim 5 wherein said process is RIE.

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PCC; and

- 11. A sub-atmospheric downstream pressure control apparatus as in claim 5 wherein said process is PECVD.
- 12. A downstream pressure control method, comprising controlling a flow of process gas into a process chamber; said method characterized by: providing a flow of gas into a pressure control chamber (PCC) connected in serial fluidic communication downstream from said process chamber; controlling fluid flow with a first flow restricting element (FRE) located in serial fluidic communication downstream from said process chamber and upstream from said
 - controlling the pressure at said process chamber by adjusting the pressure in said PCC to impact the pressure gradient over said first flow restricting element.
 - 13. A method for sub-atmospheric reactive gas abatement, characterized by: providing a substantial pressure gradient at an inlet to an abatement space; providing a substantial pressure gradient at an outlet from said abatement space; flowing a reactive abatement gas into said abatement space;
 - reacting with process gas exhaust effluents to produce substantially stable and inert solid; and
 - substantially localizing said substantially stable and inert solid within said abatement chamber.
 - 14. A method for sub-atmospheric reactive gas abatement of process gas exhaust effluent, said method characterized by: providing a substantial pressure gradient at an inlet to an abatement space;
 - providing a substantial pressure gradient at an outlet from said abatement space;
- flowing a reactive abatement gas into said abatement space; reacting said reactive abatement gas with said process gas exhaust effluent to produce a substantially volatile effluent gas; and

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transporting said substantially voiatile effluent gas through a pump foreline and pump substantially without further reaction and substantially without growth of film deposits.

- 15. A wall-protected process chamber (710, 730), comprising:
- 5 an external enclosure (602);
 - a gas permeable internal enclosure (604) disposed within said external metallic enclosure and enclosing said process chamber;
 - a seal (608, 610) between said internal enclosure and said external metallic enclosure, said internal enclosure and said external enclosure defining a substantially sealed space (606) between the outer wall of said internal enclosure and the inner wall of said external metallic enclosure; and
 - a source (612) of a pressurized inert gas in fluid communication with said sealed space; whereby said pressurized inert gas flows through said gas permeable internal enclosure to protect said process chamber wall.

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